

EVVOSEMI[®]

THINK CHANGE DO



ESD



TVS



MOS



LDO



Diode



Sensor



DC-DC

Product Specification

▶ Domestic	Part Number	BSZ100N06LS3G
▶ Overseas	Part Number	BSZ100N06LS3G
▶ Equivalent	Part Number	BSZ100N06LS3G

EV is the abbreviation of name EVVO

60V N-Channel Enhancement Mode MOSFET

Description

The BSZ100N06LS3G uses advanced trench technology to provide excellent $R_{DS(ON)}$, low gate charge and operation with gate voltages as low as 4.5V. This device is suitable for use as a Battery protection or in other Switching application.

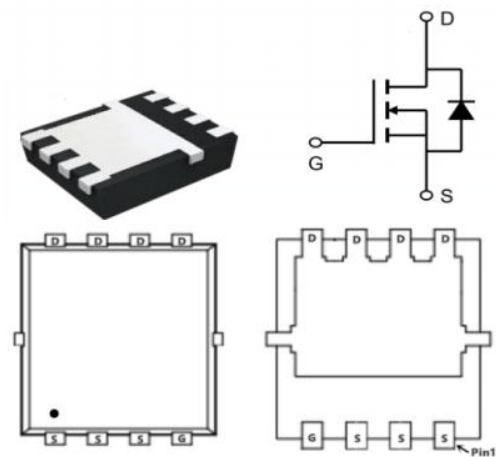
Application

- Battery protection
- Load switch
- Uninterruptible power supply

Product Summary

$V_{DS} = 60V$ $I_D = 50A$
 $R_{DS(ON)} < 10.3\ m\Omega$ @ $V_{GS}=10V$
 $R_{DS(ON)} < 14.0\ m\Omega$ @ $V_{GS}=4.5V$

PDFN3*3-8LPin Configuration



Absolute Maximum Ratings

Symbol	Parameter	Rating	Units
V_{DS}	Drain-Source Voltage	60	V
V_{GS}	Gate-Source Voltage	± 20	V
$I_D@T_C=25^{\circ}C$	Continuous Drain Current, V_{GS} @ 10V ¹	50	A
$I_D@T_C=100^{\circ}C$	Continuous Drain Current, V_{GS} @ 10V ¹	31	A
I_{DM}	Pulsed Drain Current ²	120	A
EAS	Single Pulse Avalanche Energy ³	80	mJ
I_{AS}	Avalanche Current	40	A
$P_D@T_C=25^{\circ}C$	Total Power Dissipation ⁴	41	W
T_{STG}	Storage Temperature Range	-55 to 150	$^{\circ}C$
T_J	Operating Junction Temperature Range	-55 to 150	$^{\circ}C$
$R_{\theta JA}$	Thermal Resistance Junction-ambient ¹ ($t \leq 10S$)	35	$^{\circ}C/W$
	Thermal Resistance Junction-ambient ¹ (Steady State)	55	$^{\circ}C/W$
$R_{\theta JC}$	Thermal Resistance Junction-case ¹	3	$^{\circ}C/W$

60V N-Channel Enhancement Mode MOSFET

Electrical Characteristics (T_J=25°C unless otherwise specified)

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
BV _{DSS}	Drain-Source Breakdown Voltage	V _{GS} =0V, I _D =250uA	60	---	---	V
R _{DS(ON)}	Static Drain-Source On-Resistance ²	V _{GS} =10V, I _D =20A	---	8.2	10.3	mΩ
		V _{GS} =4.5V, I _D =20A	---	10.5	14.0	mΩ
V _{GS(th)}	Gate Threshold Voltage	V _{DS} =V _{GS} , I _D =250uA	1.1	1.6	2.1	V
I _{DSS}	Drain-Source Leakage Current	V _{DS} =48V, V _{GS} =0V, T _J =25°C	---	---	1	uA
		V _{DS} =48V, V _{GS} =0V, T _J =55°C	---	---	5	
I _{GSS}	Gate-Source Leakage Current	V _{GS} =±20V, V _{DS} =0V	---	---	±100	nA
R _g	Gate Resistance	V _{DS} =0V, V _{GS} =0V, f=1MHz	---	1.2	---	Ω
Q _g	Total Gate Charge (10V)	V _{DS} =30V, V _{GS} =10V, I _D =18A	---	57	---	nC
Q _{gs}	Gate-Source Charge		---	8.7	---	
Q _{gd}	Gate-Drain Charge		---	14	---	
T _{d(on)}	Turn-On Delay Time	V _{DD} =30V, V _{GS} =10V, R _G =3.3Ω, I _D =20A	---	16.2	---	ns
T _r	Rise Time		---	41.2	---	
T _{d(off)}	Turn-Off Delay Time		---	56.4	---	
T _f	Fall Time		---	16.2	---	
C _{iss}	Input Capacitance	V _{DS} =30V, V _{GS} =0V, f=1MHz	---	1260	---	pF
C _{oss}	Output Capacitance		---	139	---	
C _{rss}	Reverse Transfer Capacitance		---	87	---	
I _S	Continuous Source Current ^{1,5}	V _G =V _D =0V, Force Current	---	---	50	A
V _{SD}	Diode Forward Voltage ²	V _{GS} =0V, I _S =1A, T _J =25°C	---	---	1.2	V
t _{rr}	Reverse Recovery Time	I _F =20A, dI/dt=100A/μs, T _J =25°C	---	22	---	nS
Q _{rr}	Reverse Recovery Charge	T _J =25°C	---	72	---	nC

Note :

- 1.The data tested by surface mounted on a 1 inch² FR-4 board with 20Z copper.
- 2.The data tested by pulsed, pulse width ≤ 300us, duty cycle ≤ 2%
- 3.The EAS data shows Max. rating. The test condition is V_{DD}=50V, V_{GS}=10V, L=0.1mH, I_{AS}=40A
- 4.The power dissipation is limited by 150°C junction temperature
- 5.The data is theoretically the same as I_D and I_{DM}, in real applications, should be limited by total power dissipation.

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Typical Performance Characteristics

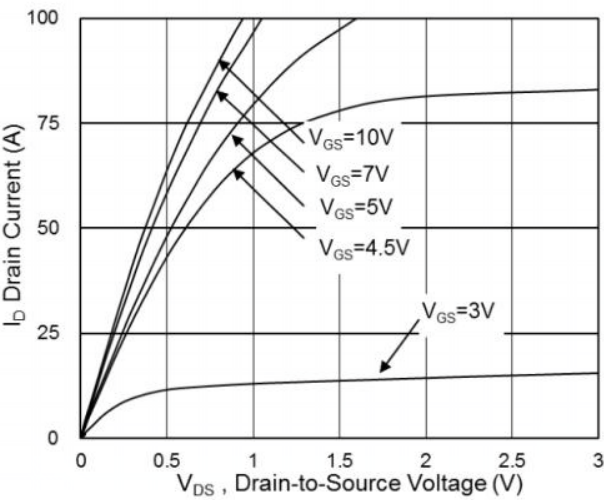


Fig.1 Typical Output Characteristics

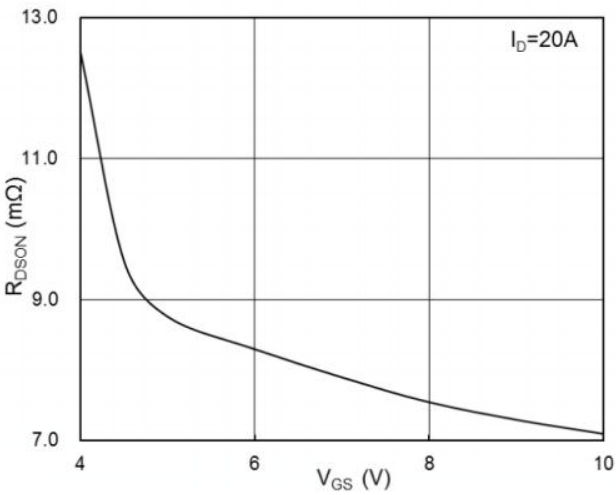


Fig.2 On-Resistance v.s Gate-Source

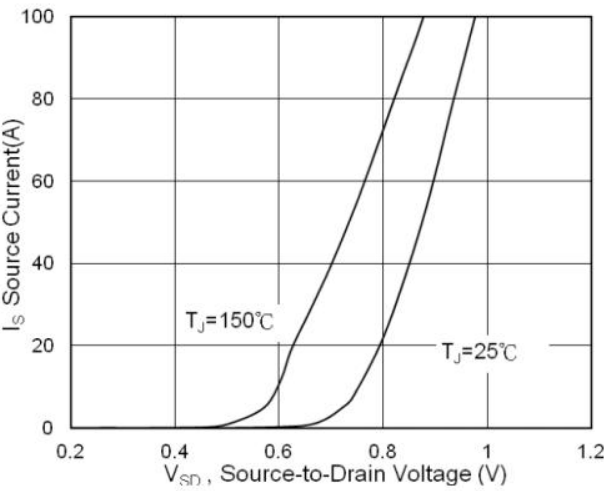


Fig.3 Forward Characteristics of Reverse

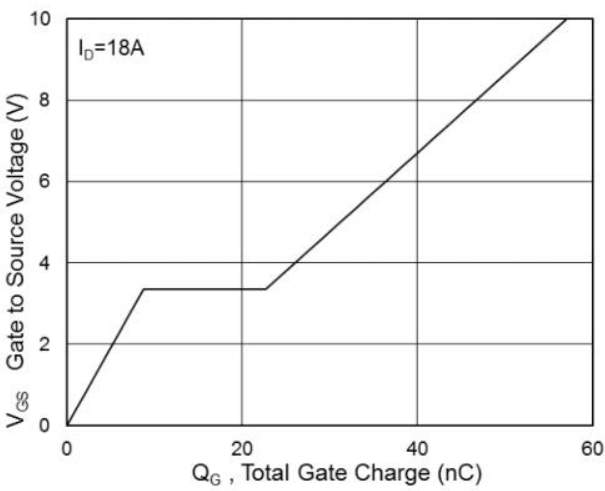


Fig.4 Gate-Charge Characteristics

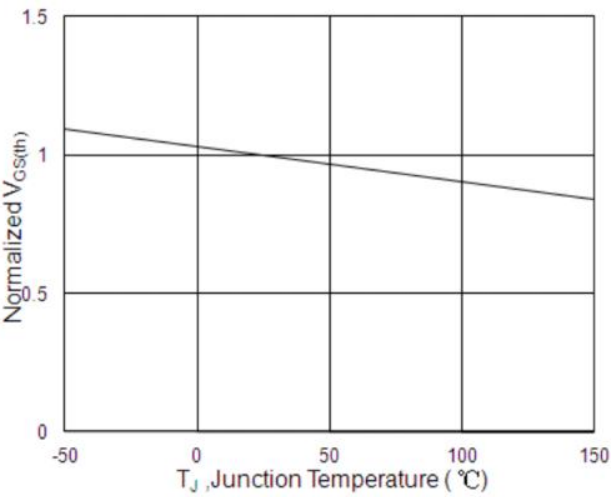


Fig.5 Normalized $V_{GS(th)}$ vs. T_J

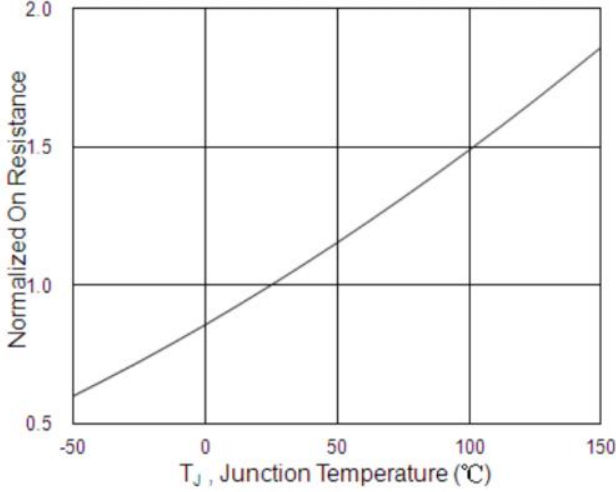
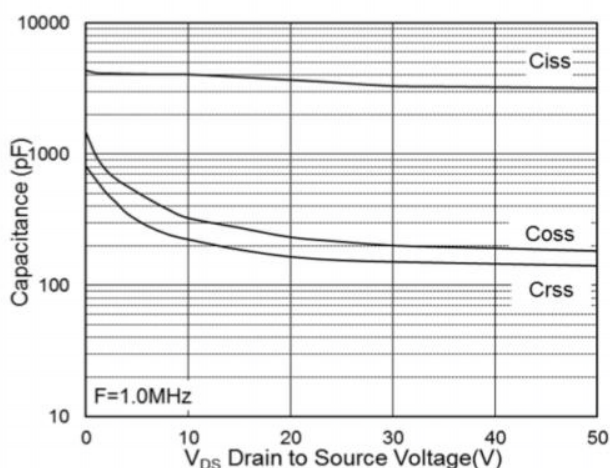
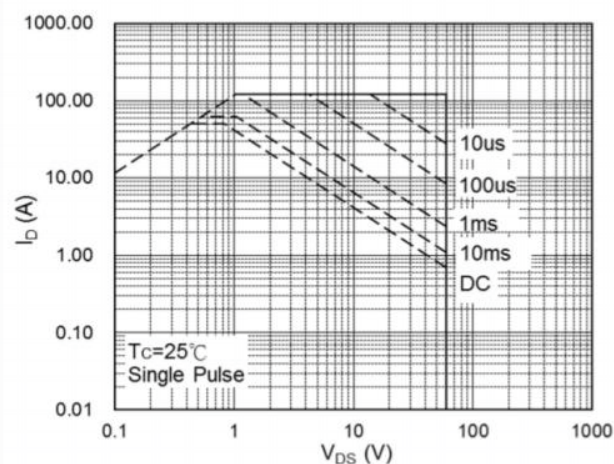
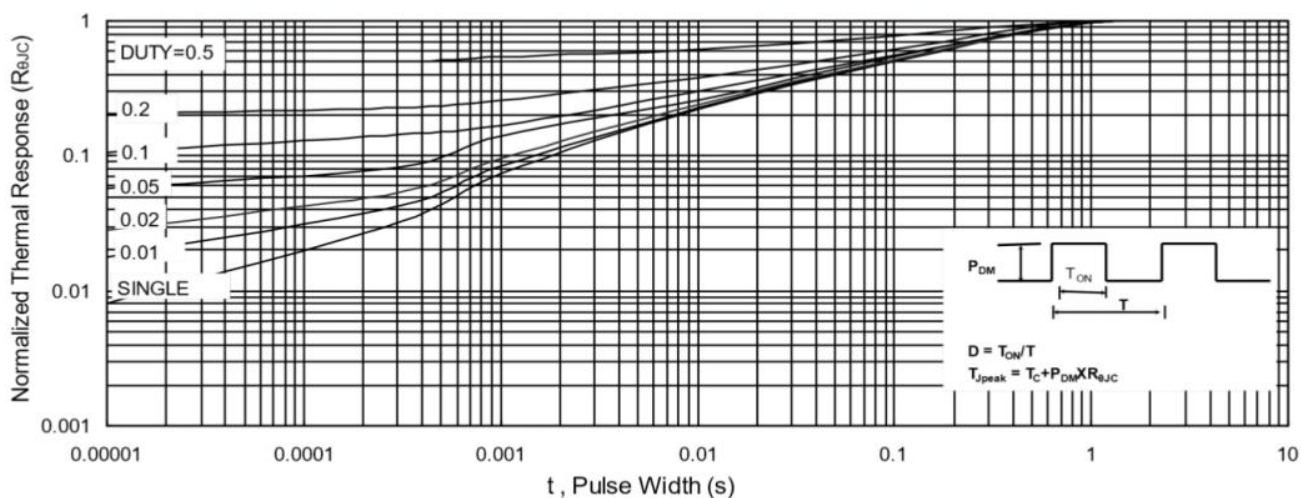
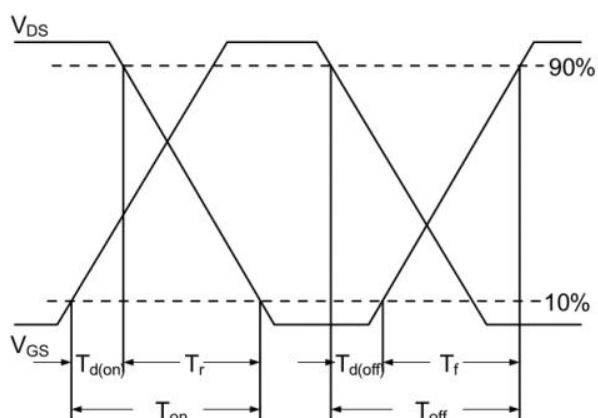
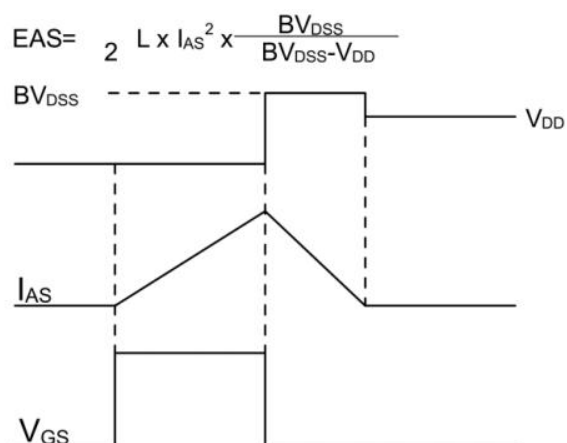


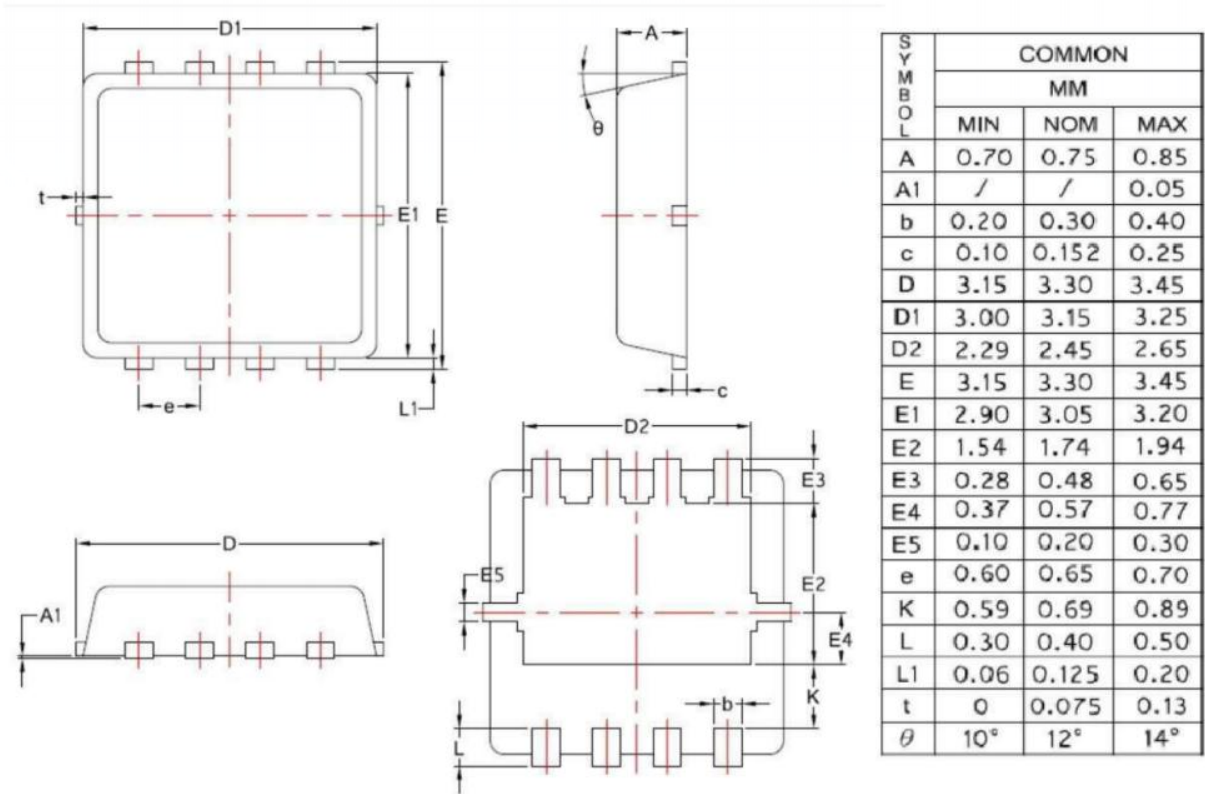
Fig.6 Normalized $R_{DS(on)}$ vs. T_J

60V N-Channel Enhancement Mode MOSFET


Fig.7 Capacitance

Fig.8 Safe Operating Area

Fig.9 Normalized Maximum Transient Thermal Impedance

Fig.10 Switching Time Waveform

Fig.11 Unclamped Inductive Switching Waveform

60V N-Channel Enhancement Mode MOSFET

Package Mechanical DataPDFN3*3-8L



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